

NANOSTRUCTURING AND CHARACTERIZATION

Nanostructuring

- Electron beam lithography (EBL)
- UV nanoimprint lithography (UV-NIL)
- Focused ion and electron beam etching & deposition (FIB)
- Chip modification and repair

Characterization

- Physical and electrical analysis
 - SEM, TEM, EDX, XPS, SNMS
 - AFM, SSRM, SCM, c-AFM, TUNA
 - Elymat, μ -PCD, SPV, DLTS
- Device characterization (parameters and reliability)
- Failure analysis
- TEM sample preparation
- Cross-sectioning

CONTACT

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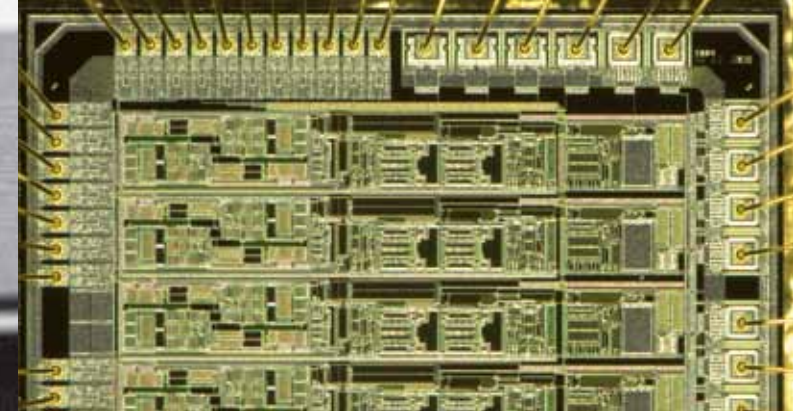
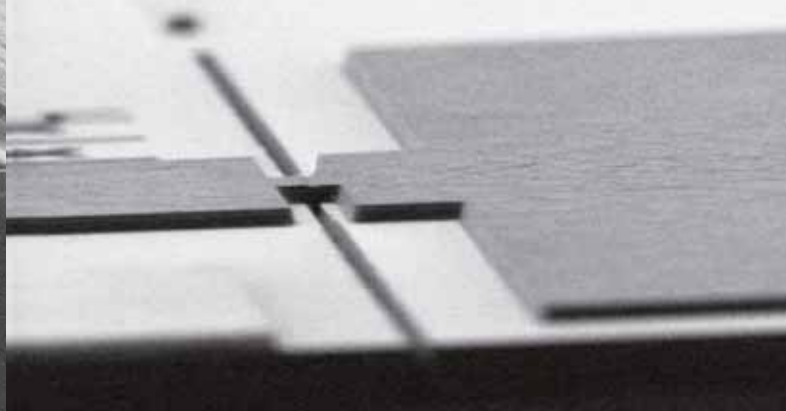
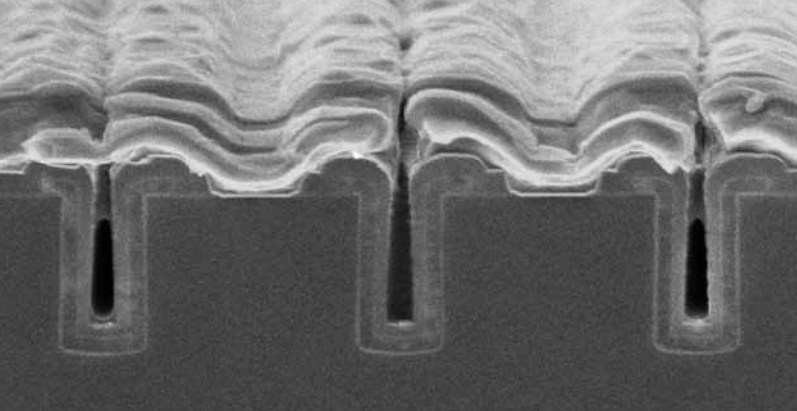
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**PROVIDING A UNIQUE
PLATFORM FOR ACADEMIC
AND INDUSTRIAL COMMUNITIES**

SOLUTIONS & SERVICES ON NANO AND MICRO SCALE

- **microelectronics & energy**
- **sensors & actuators**
- **photonics & rf technology**
- **material science**
- **bio technology & medicine**





PROCESSES

Diffusion, Oxidation, Annealing:

Furnace & RTP

Implantation:

Low to high energies
Large variety of ion species

Layer deposition:

ALD & MOCVD
PECVD & LPCVD
Sputtering & evaporation

Dry etching:

RIE & ICP

Wet chemistry:

Cleaning & etching

Photolithography:

Mask aligner & laser direct writing

Metrology:

Optical, mechanical & electrical

**For wafers and substrates
of Si, SiC, Ge, quartz and others
from test samples up to 200 mm diameter**

DEVICE PROTOTYPING

Customized sample preparation

- Complete process sequences
- Micro and nano scale patterning

Development of novel devices

- Feasibility studies
- Simulation and proof of concept
- Prototype manufacturing

Integration of electron devices

- Passives
- Logic
- Power electronics
- Piezoelectric
- Sensors and actuators

CIRCUIT PROTOTYPING

Design of monolithically integrated smart-power circuits in high-voltage automotive technologies

- Driver circuits for power devices & lighting systems
- Energy management & conversion circuits
- Sensor circuits & microsystems

Design flow service for smart-power circuits

- Circuit & system modeling
- Circuit design & simulation
- Layout design
- Assembly & test

Failure analysis

- Failure analysis for devices, circuits, and systems
- Decapsulation and deprocessing of integrated circuits